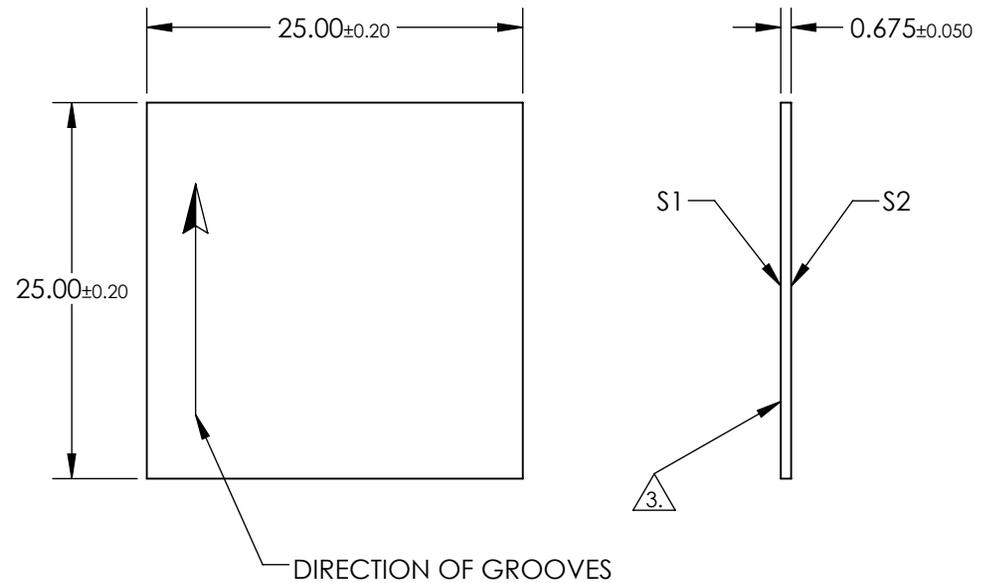
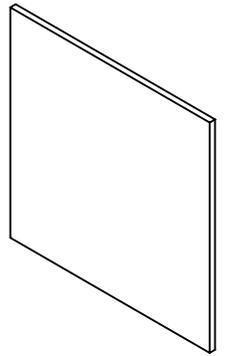
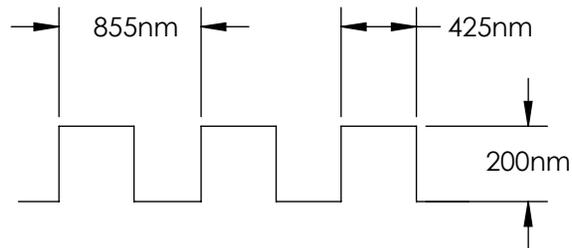


NOTES:

1. SUBSTRATE MATERIAL:
Single Crystal Silicon
2. PERIOD: $855 \pm 42.75\text{nm}$
LINE WIDTH: $425 \pm 42.5\text{nm}$
GROOVE DEPTH: $200 \pm 30\text{nm}$
3.  RIE TREATED SURFACE
4. RoHS COMPLIANT



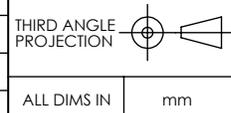
CROSS SECTION VIEW OF GRATING SURFACE



**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	60-40 (within CA)	FINE GRIND
CLEAR APERTURE	24.00 x 24.00	N/A
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED



EO® **Edmund Optics**®

TITLE	II-VI LightSmyth™ 855nm, 200nm Groove Depth, 25mm Sq. Linear Silicon Nanostamp
DWG NO	16856
SHEET	1 OF 1